

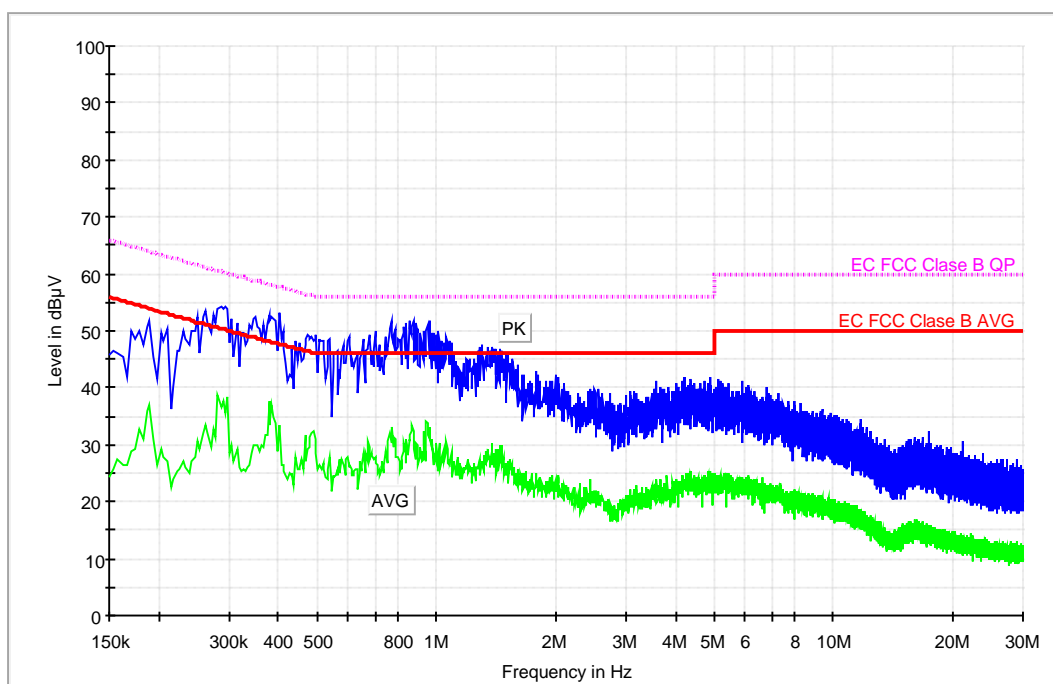
Continuous conducted emission: CC0103L1 (Peak and Average)

EMC32 Report

Test Information

Proyecto: 25810Biem.003
 Empresa: NEONODE
 Muestra: M/01
 Modo operacion: MO#03
 Fecha: 2007-05-15 19:50
 Setup: EMI conducted
 Mode: EBP ON. TCH 1900MHz. Cargando baterías. Ruido en la fase.

EC FCC Clase B ESPI CC



Max PK-AVG

Frequency (MHz)	MaxPeak-ClearWrite (dBμV)	Average-ClearWrite (dBμV)	Comment
0.190000	51.8	37.1	
0.210000	50.4	27.1	
0.250000	52.4	30.7	
0.294000	54.1	35.7	
0.314000	51.6	29.2	
0.378000	52.8	37.5	
0.402000	53.1	33.3	
0.770000	51.7	30.1	
0.830000	50.6	30.3	
0.842000	51.4	31.0	
0.874000	51.8	32.3	
0.890000	51.5	30.4	
0.950000	50.9	33.7	

Report No:
25810RET.201

Date: 2007-08-03

Page: 5 of 7

Annex C

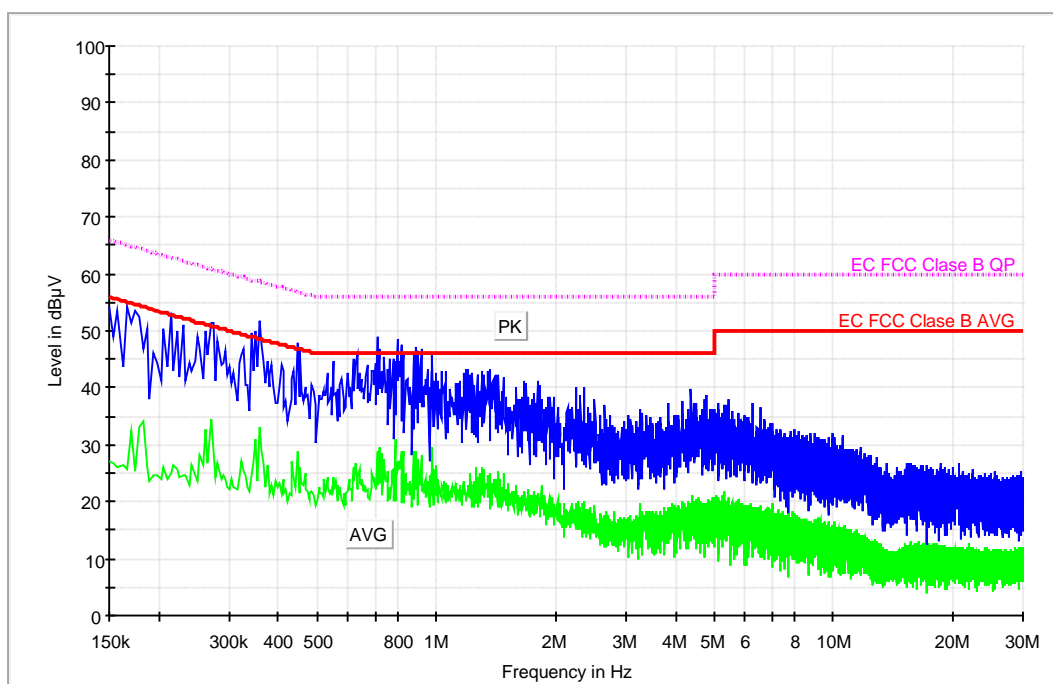
Continuous conducted emission: CC01040N (Peak and Average)

EMC32 Report

Test Information

Proyecto: 25810Biem.003
 Empresa: NEONODE
 Muestra: M/01
 Modo operacion: MO#04
 Fecha: 2007-05-15 20:36
 Setup: EMI conducted
 Mode: EBP ON. TCH 850MHz. Cargando baterías. Ruido en el neutro.

EC FCC Clase B ESPI CC



Max PK-AVG

Frequency (MHz)	MaxPeak-ClearWrite (dBµV)	Average-ClearWrite (dBµV)	Comment
0.150000	54.1	27.0	
0.166000	54.1	25.5	
0.206000	50.2	25.9	
0.214000	53.3	25.1	
0.222000	50.0	25.7	
0.230000	51.2	24.7	
0.250000	48.9	23.6	
0.270000	51.5	34.7	
0.282000	48.3	26.7	
0.342000	49.8	24.8	
0.350000	50.1	31.1	
0.358000	51.8	33.2	
0.710000	49.0	29.0	

Report No:
25810RET.201

Date: 2007-08-03

Page: 6 of 7

Annex C

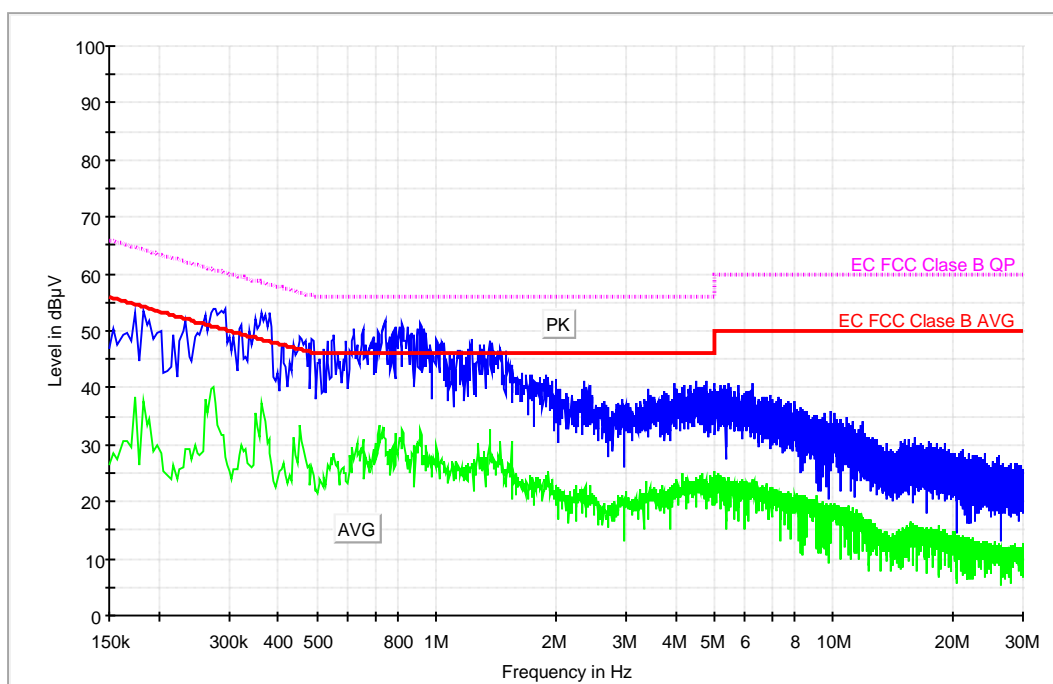
Continuous conducted emission: CC0104L1 (Peak and Average)

EMC32 Report

Test Information

Proyecto: 25810Biem.003
 Empresa: NEONODE
 Muestra: M/01
 Modo operacion: MO#04
 Fecha: 2007-05-15 20:41
 Setup: EMI conducted
 Mode: EBP ON. TCH 850MHz. Cargando baterías. Ruido en la fase.

EC FCC Clase B ESPI CC



Max PK-AVG

Frequency (MHz)	MaxPeak-ClearWrite (dBµV)	Average-ClearWrite (dBµV)	Comment
0.174000	53.2	38.2	
0.182000	53.4	37.6	
0.234000	51.7	29.3	
0.278000	54.0	37.3	
0.322000	51.0	29.8	
0.382000	53.3	28.7	
0.622000	50.3	27.6	
0.654000	50.5	31.0	
0.742000	51.7	30.8	
0.806000	50.8	31.3	
0.822000	51.4	32.9	
0.894000	50.3	30.3	
0.910000	51.4	32.6	

Report No:
25810RET.201

Date: 2007-08-03

Page: 7 of 7

Annex C

ANNEX D

PHOTOGRAPHS (Number of photographs: 7)

Report No.: 25810RET.201

1. Equipment (front view)



Report No.:
25810RET.201

Date: 2007-08-03

Page: 2 of 8

Annex D

2. Equipment (back view)



Report No.:
25810RET.201

Date: 2007-08-03

Page: 3 of 8

Annex D

3. Equipment for conducted measurements



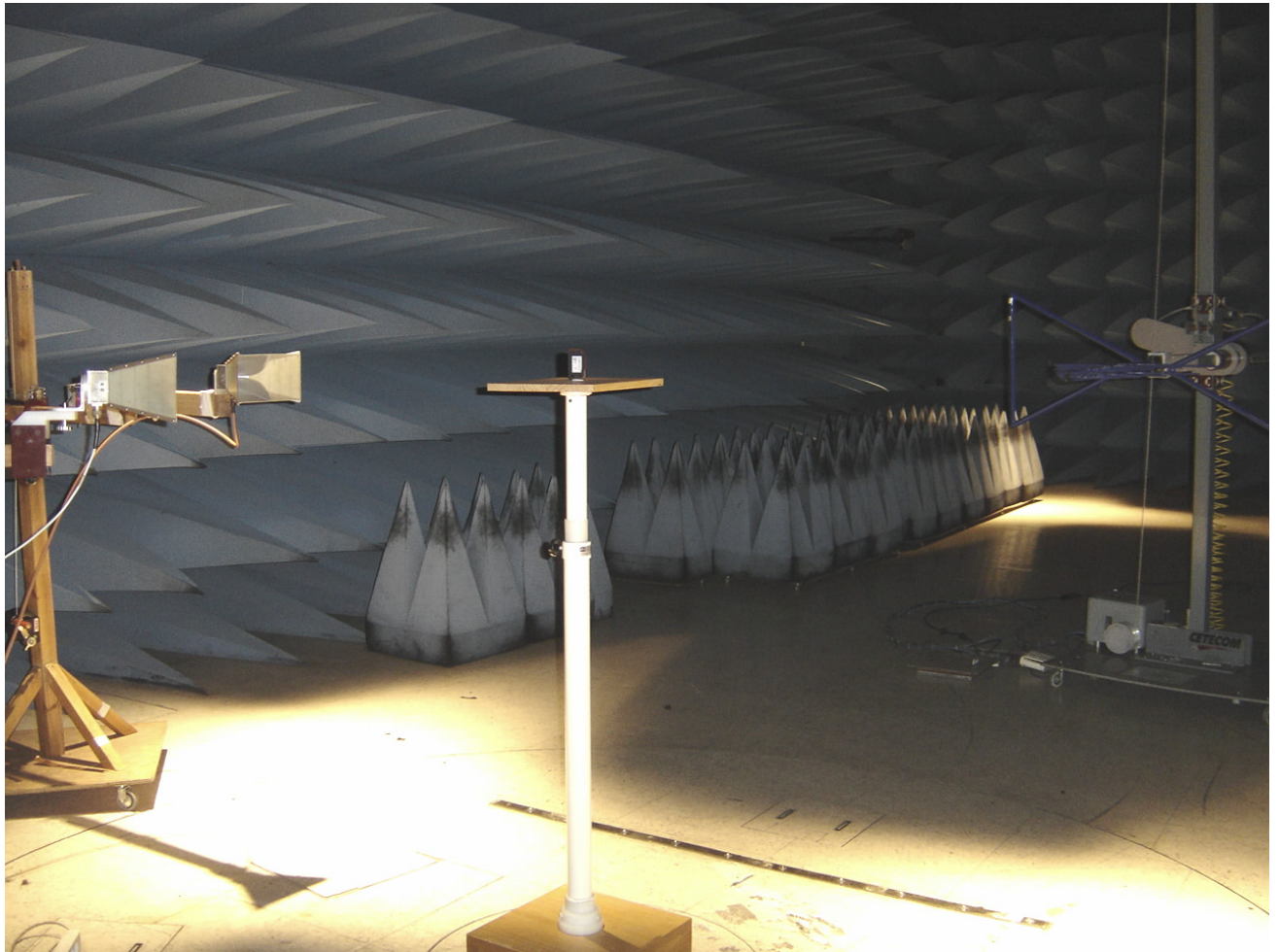
Report No.:
25810RET.201

Date: 2007-08-03

Page: 4 of 8

Annex D

4. General test set-up for radiated measurements.



Report No.:
25810RET.201

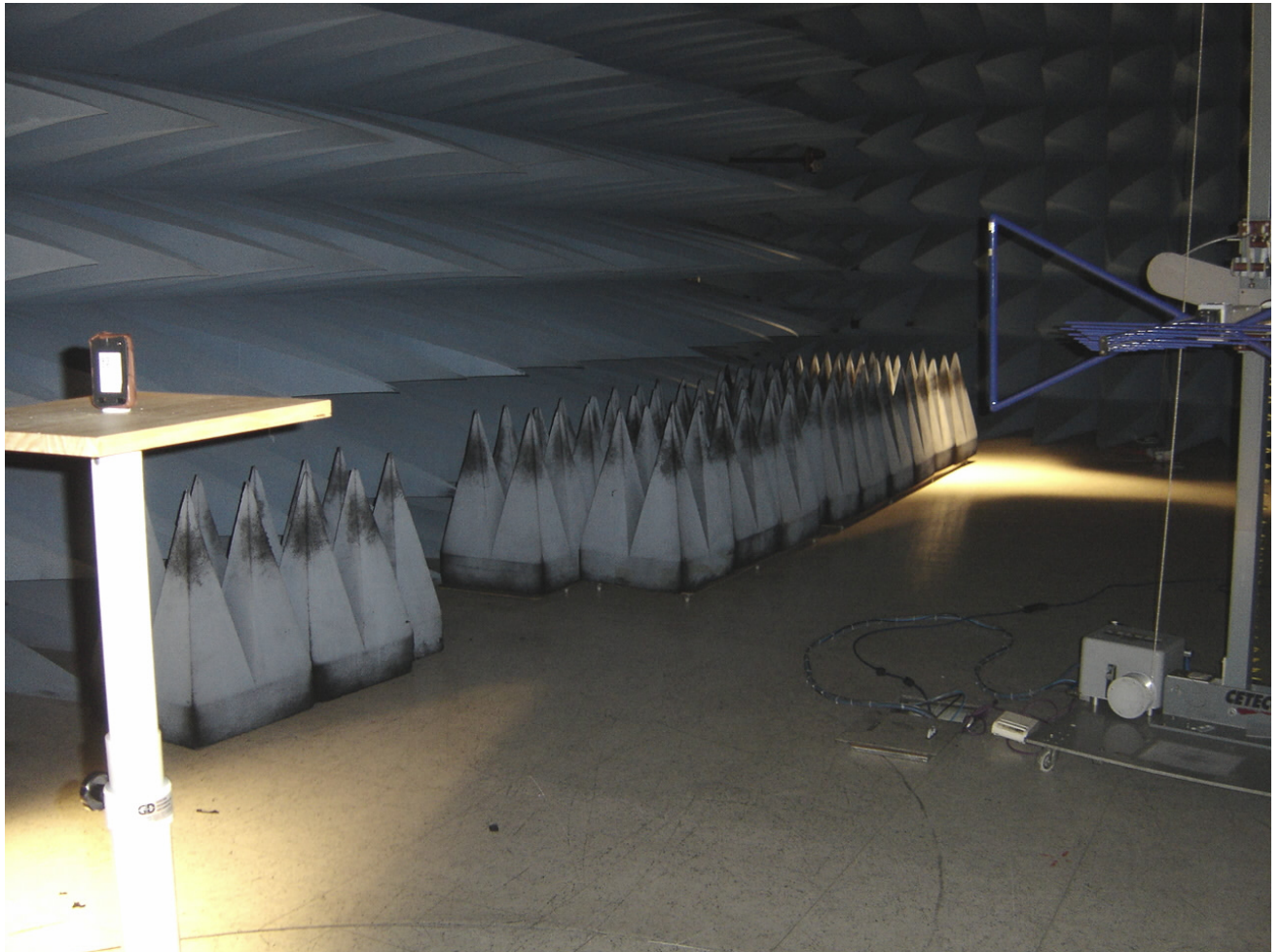
Date: 2007-08-03

FET18_00.DOC

Page: 5 of 8

Annex D

5. Test set-up for radiated measurements below 1 GHz.



Report No.:
25810RET.201

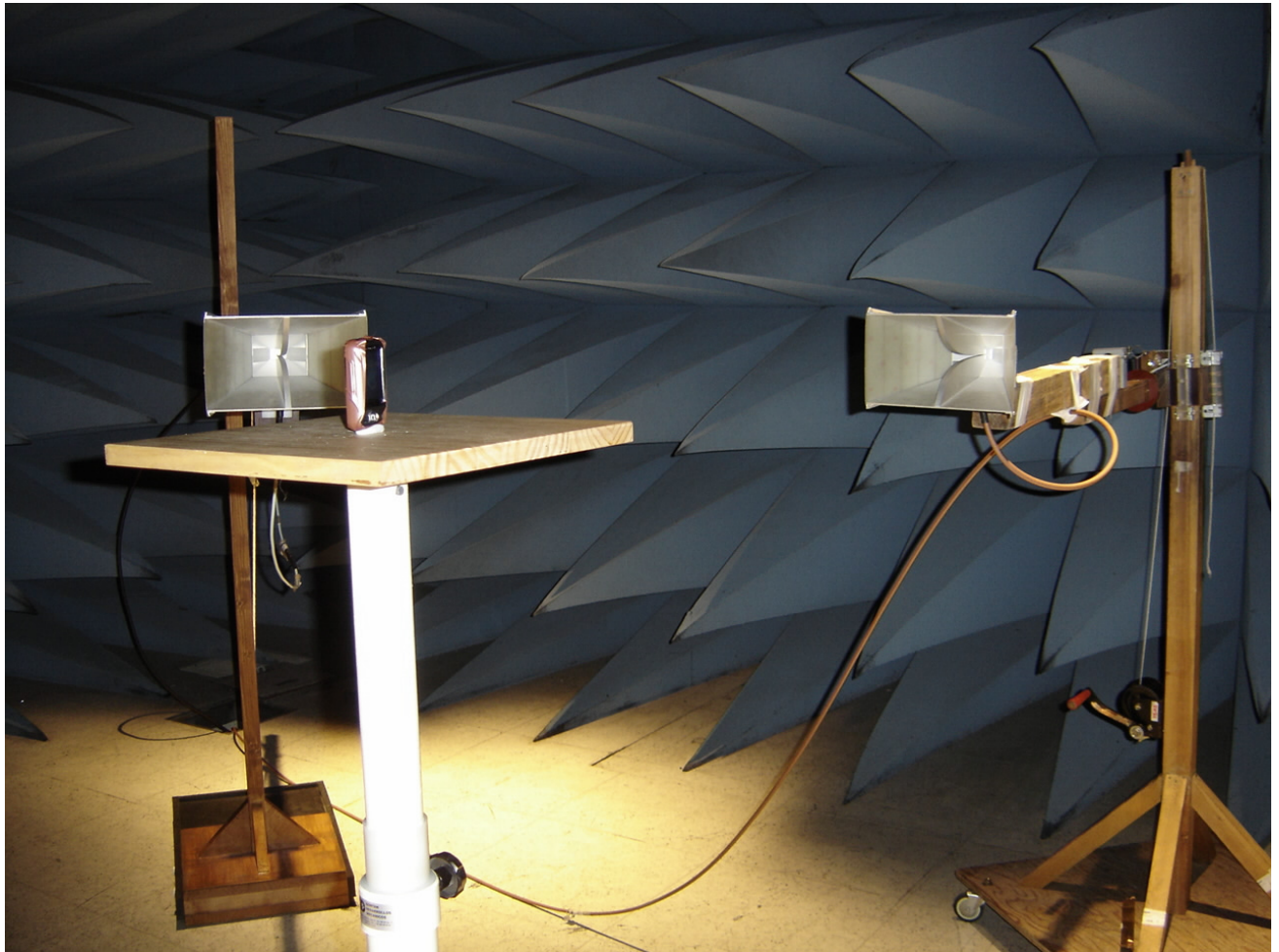
Date: 2007-08-03

FET18_00.DOC

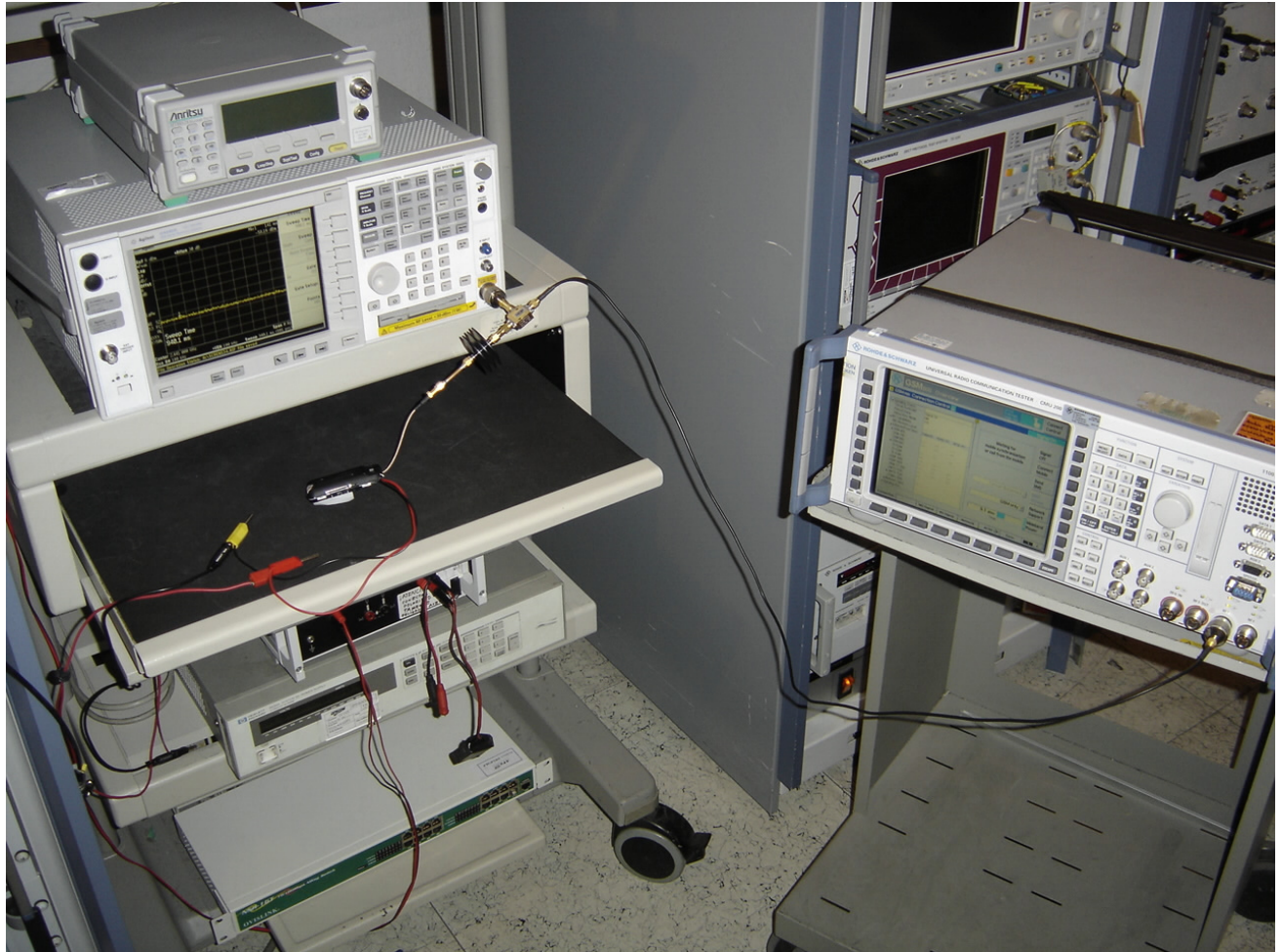
Page: 6 of 8

Annex D

6. Test set-up for radiated measurements above 1 GHz.



7. Test set-up for conducted measurements.



Report No.:
25810RET.201

Date: 2007-08-03

FET18_00.DOC

Page: 8 of 8

Annex D